


<b>Search Notes</b>  	<b>Application/Control No.</b>  10826090	<b>Applicant(s)/Patent Under Reexamination</b>  CHEN, SHI-SHIEN
	<b>Examiner</b>  Neway, Samuel G	<b>Art Unit</b>  2626

### SEARCHED

Class	Subclass	Date	Examiner
704	8 (with text)	01/22/08	SN
341	50-107 (with text)	01/31/08	SN

### SEARCH NOTES

Search Notes	Date	Examiner
EAST: Text, Assignee, Inventor, Forward & Backward, and PLUS Search	08/14/07	SN
Consulted: P. Edouard	08/14/07	SN
Consulted: T. Smits	08/15/07	SN
Updated EAST Search	01/22/08	SN
STIC Search	01/30/08	SN
Consulted: P. Harper	01/29/08	SN
EAST: Updated Search	05/15/08	SN

### INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
704	8	05/15/08	SN
341	50	05/15/08	SN